

IEC QUALITY ASSESSMENT SYSTEM (IECQ) covering Electronic Components, Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Approval

Independent Testing Laboratory

IECQ Certificate No.: IECQ-L JQAJP 13.0003-01 CB Certificate No.: JQAQ0010-002-T

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This certificate has been issued based on the one issued by RCJ under IECQ Cert.No.IECQ-L RCJ 10.0014 dated on 2000/07/28, due to the duty taken over by JQA.

Type of Components

QC 300000 (Fixed capacitor) QC 230000 (Printed circuit board) QC 700000 (Discrete devices and Integrated circuits)

ENVIRONMENTAL TEST

IEC 60068-2-1 (Test A: Cold) IEC 60068-2-2 (Test B: Dry heat) IEC 60068-2-14 (Test N: Change of temperature) IEC 60068-2-38 (Test Z/AD: Composite temperature/humidity cyclic test) IEC 60068-2-42 (Test Kc: Sulphur dioxide test for contacts and connections) IEC 60068-2-43 (Test Kd: Hydrogen sulphide test for contacts and connections) IEC 60068-2-78 (Test Cab: Damp heat, steady state)

MECHANICAL TEST

IEC 60068-2-6 (Test Fc: Vibration (sinusoidal)) IEC 60068-2-64 (Test Fh: Vibration (broad-band random))

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